

# Low-temperature photoluminescence spectroscopy for LGAD structures

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A short introduction to the measurement method low temperature photoluminescence (LTPL) spectroscopy is given. Samples from a low gain avalanche detector processing run are studied by LTPL before and after electron irradiation. In carbon doped samples the characteristic G-line is found after electron irradiation.

**Primary author:** LAUER, Kevin (CIS Institut fuer Mikrosensorik GmbH (DE))

**Co-authors:** Dr SCHULZE, Dirk (TU-Ilmenau); Prof. KRISCHOK, Stefan (TU-Ilmenau); RODER, Ralf Mario (CIS Institut fuer Mikrosensorik GmbH (DE)); Prof. ORTLEPP, Thomas (CIS Forschungsinstitut für Mikrosensorik)

**Presenter:** LAUER, Kevin (CIS Institut fuer Mikrosensorik GmbH (DE))

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